

FEATURES

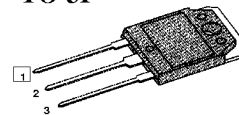
- ◆ Avalanche Rugged Technology
- ◆ Rugged Gate Oxide Technology
- ◆ Lower Input Capacitance
- ◆ Improved Gate Charge
- ◆ Extended Safe Operating Area
- ◆ Lower Leakage Current: 10 μ A (Max.) @ $V_{DS} = 400V$
- ◆ Low $R_{DS(ON)}$: 0.254 Ω (Typ.)

$$BV_{DSS} = 400\text{ V}$$

$$R_{DS(on)} = 0.3\Omega$$

$$I_D = 17\text{ A}$$

TO-3P



1.Gate 2. Drain 3. Source

Absolute Maximum Ratings

Symbol	Characteristic	Value	Units
V_{DSS}	Drain-to-Source Voltage	400	V
I_D	Continuous Drain Current ($T_C=25^\circ\text{C}$)	17	A
	Continuous Drain Current ($T_C=100^\circ\text{C}$)	10.8	
I_{DM}	Drain Current-Pulsed (1)	68	A
V_{GS}	Gate-to-Source Voltage	± 30	V
E_{AS}	Single Pulsed Avalanche Energy (2)	1156	mJ
I_{AR}	Avalanche Current (1)	17	A
E_{AR}	Repetitive Avalanche Energy (1)	20.2	mJ
dv/dt	Peak Diode Recovery dv/dt (3)	4.0	V/ns
P_D	Total Power Dissipation ($T_C=25^\circ\text{C}$)	202	W
	Linear Derating Factor	1.61	W/ $^\circ\text{C}$
T_J, T_{STG}	Operating Junction and Storage Temperature Range	- 55 to +150	$^\circ\text{C}$
T_L	Maximum Lead Temp. for Soldering Purposes, 1/8. from case for 5-seconds	300	

Thermal Resistance

Symbol	Characteristic	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case	--	0.62	$^\circ\text{C/W}$
$R_{\theta CS}$	Case-to-Sink	0.24	--	
$R_{\theta JA}$	Junction-to-Ambient	--	40	

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Rev. B

Electrical Characteristics ($T_C=25^\circ\text{C}$ unless otherwise specified)

Symbol	Characteristic	Min.	Typ.	Max.	Units	Test Condition
BV_{DSS}	Drain-Source Breakdown Voltage	400	--	--	V	$V_{GS}=0V, I_D=250\mu A$
$\Delta BV/\Delta T_J$	Breakdown Voltage Temp. Coeff.	--	0.46	--	V/ $^\circ\text{C}$	$I_D=250\mu A$ <i>See Fig 7</i>
$V_{GS(th)}$	Gate Threshold Voltage	2.0	--	4.0	V	$V_{DS}=5V, I_D=250\mu A$
I_{GSS}	Gate-Source Leakage, Forward	--	--	100	nA	$V_{GS}=30V$
	Gate-Source Leakage, Reverse	--	--	-100		$V_{GS}=-30V$
I_{DSS}	Drain-to-Source Leakage Current	--	--	10	μA	$V_{DS}=400V$
		--	--	100		$V_{DS}=320V, T_C=125^\circ\text{C}$
$R_{DS(on)}$	Static Drain-Source On-State Resistance	--	--	0.3	Ω	$V_{GS}=10V, I_D=8.5A$ (4)
g_{fs}	Forward Transconductance	--	11.65	--	$\bar{O}$	$V_{DS}=50V, I_D=8.5A$ (4)
C_{iss}	Input Capacitance	--	2140	2780	pF	$V_{GS}=0V, V_{DS}=25V, f=1\text{MHz}$ <i>See Fig 5</i>
C_{oss}	Output Capacitance	--	305	350		
C_{rss}	Reverse Transfer Capacitance	--	134	155		
$t_{d(on)}$	Turn-On Delay Time	--	20	50	ns	$V_{DD}=200V, I_D=17A,$ $R_G=6.2\Omega$ <i>See Fig 13</i> (4) (5)
t_r	Rise Time	--	22	55		
$t_{d(off)}$	Turn-Off Delay Time	--	100	210		
t_f	Fall Time	--	32	75		
Q_g	Total Gate Charge	--	101	131	nC	$V_{DS}=320V, V_{GS}=10V,$ $I_D=17A$ <i>See Fig 6 & Fig 12</i> (4) (5)
Q_{gs}	Gate-Source Charge	--	14	--		
Q_{gd}	Gate-Drain (. Miller.) Charge	--	51.5	--		

Source-Drain Diode Ratings and Characteristics

Symbol	Characteristic	Min.	Typ.	Max.	Units	Test Condition
I_S	Continuous Source Current	--	--	17	A	Integral reverse pn-diode in the MOSFET
I_{SM}	Pulsed-Source Current (1)	--	--	68		
V_{SD}	Diode Forward Voltage (4)	--	--	1.5	V	$T_J=25^\circ\text{C}, I_S=17A, V_{GS}=0V$
t_{rr}	Reverse Recovery Time	--	385	--	ns	$T_J=25^\circ\text{C}, I_F=17A$
Q_{rr}	Reverse Recovery Charge	--	4.85	--	μC	$di_F/dt=100A/\mu s$ (4)

Notes;

- (1) Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature
(2) $L=7\text{mH}$, $I_{AS}=17A$, $V_{DD}=50V$, $R_G=27\Omega$, Starting $T_J=25^\circ\text{C}$
(3) $I_{SD} \leq 17A$, $di/dt \leq 250A/\mu s$, $V_{DD} \leq BV_{DSS}$, Starting $T_J=25^\circ\text{C}$
(4) Pulse Test: Pulse Width = $250\mu s$, Duty Cycle $\leq 2\%$
(5) Essentially Independent of Operating Temperature

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Fig 1. Output Characteristics

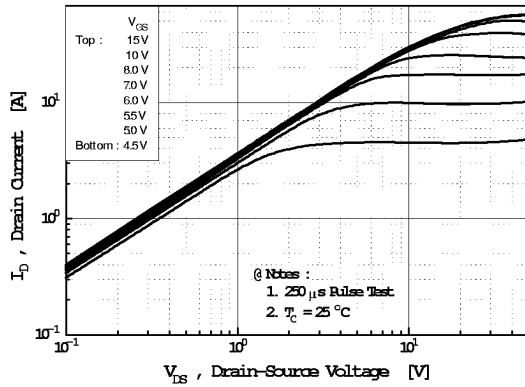


Fig 2. Transfer Characteristics

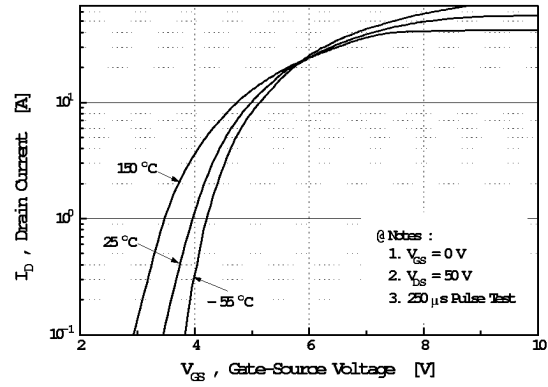


Fig 3. On-Resistance vs. Drain Current

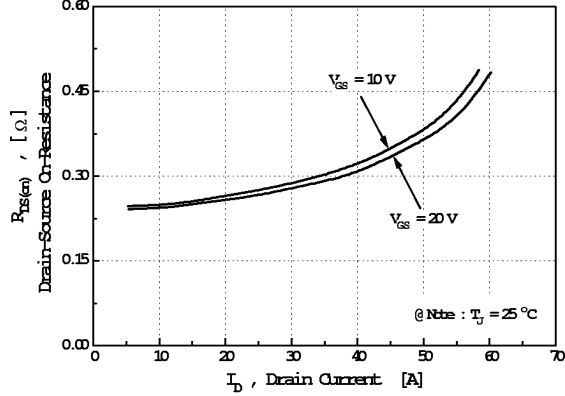


Fig 4. Source-Drain Diode Forward Voltage

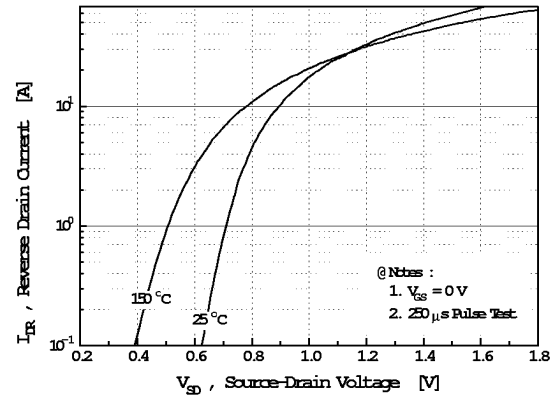


Fig 5. Capacitance vs. Drain-Source Voltage

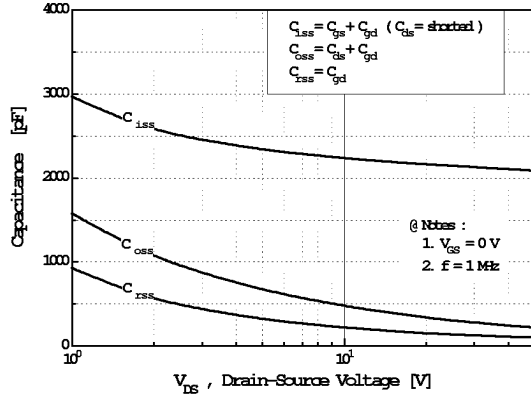


Fig 6. Gate Charge vs. Gate-Source Voltage

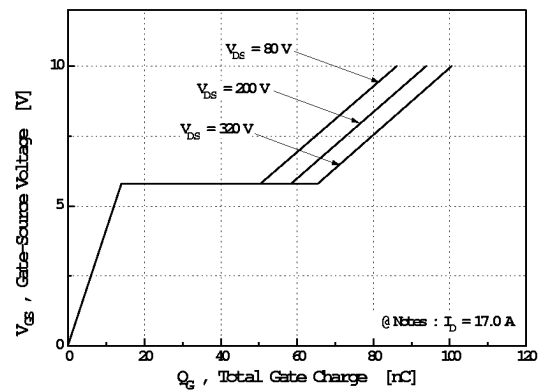


Fig 7. Breakdown Voltage vs. Temperature

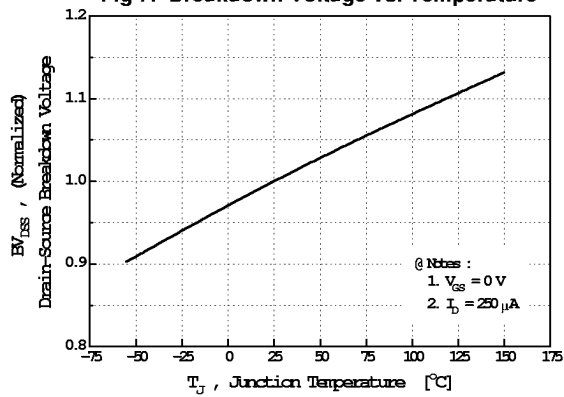


Fig 8. On-Resistance vs. Temperature

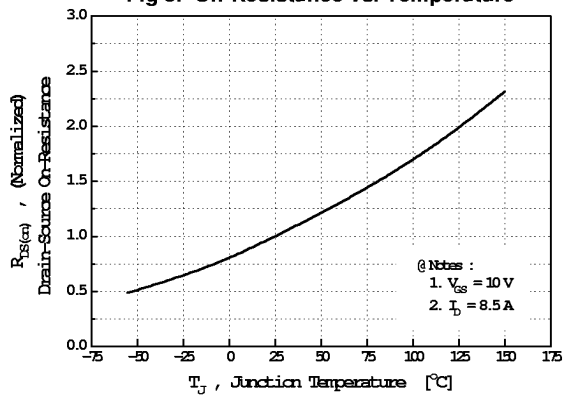


Fig 9. Max. Safe Operating Area

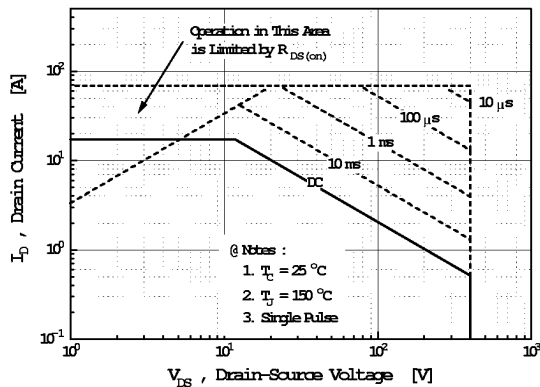


Fig 10. Max. Drain Current vs. Case Temperature

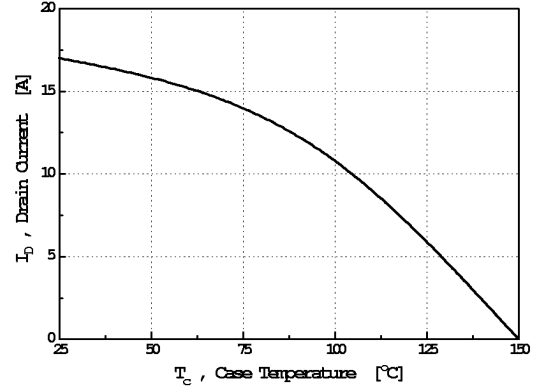


Fig 11. Thermal Response

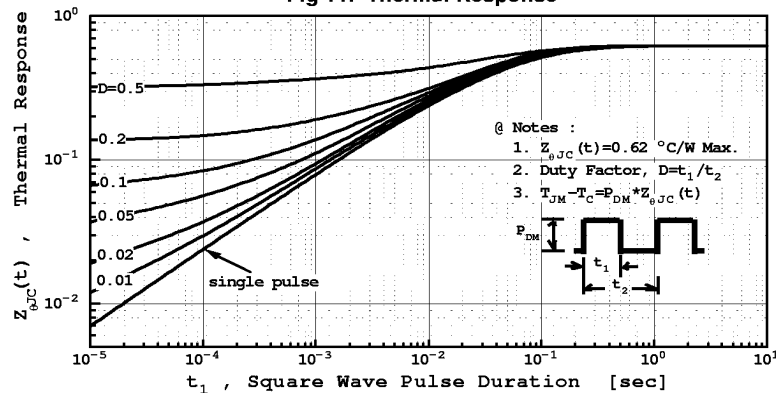


Fig 12. Gate Charge Test Circuit & Waveform

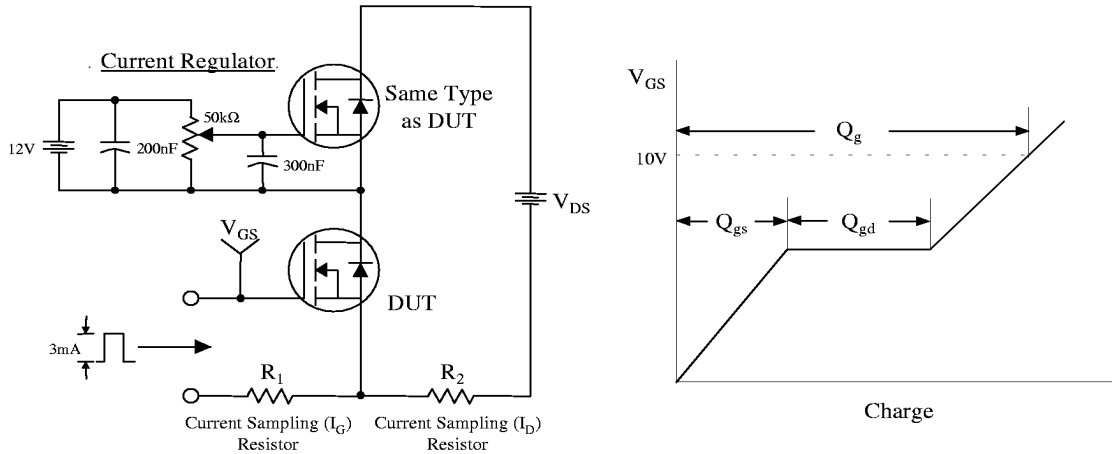


Fig 13. Resistive Switching Test Circuit & Waveforms

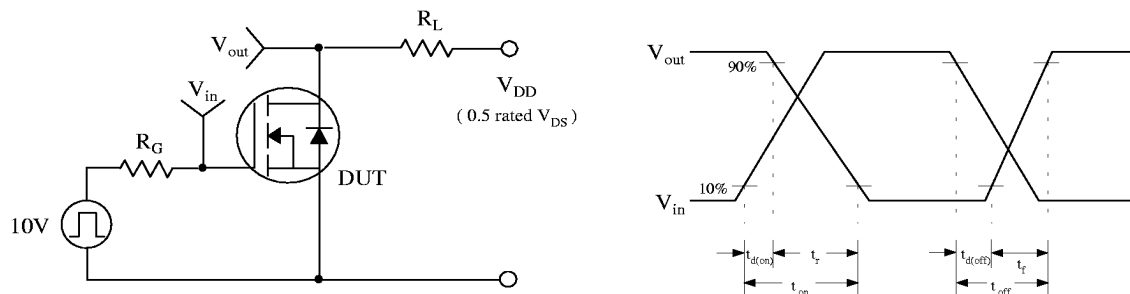
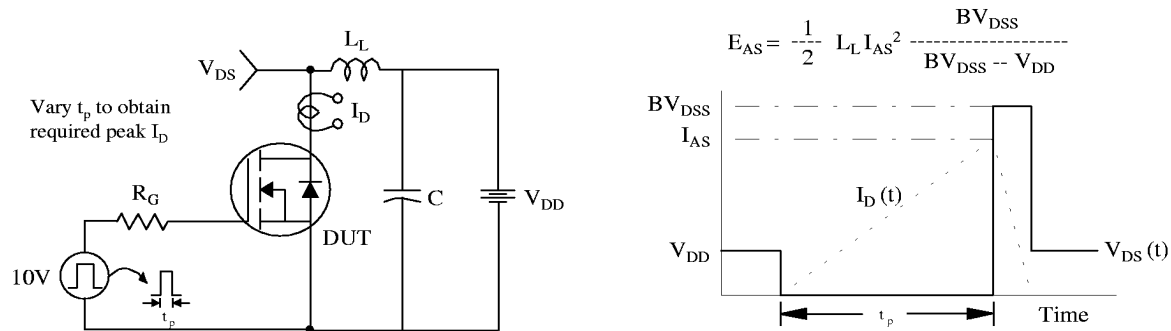


Fig 14. Unclamped Inductive Switching Test Circuit & Waveforms



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Fig 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms

